

<b>Notice of References Cited</b>	Application/Control No. 09/887,781		Applicant(s)/Patent Under Reexamination ANN ET AL.	
	Examiner Tan Dean D. Nguyen		Art Unit 3689	Page 1 of 1

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*	B	US-6,697,824	02-2004	Bowman-Amuah, Michel K.	709/229
*	C	US-2004/0059611	03-2004	Kananghinis et al.	705/007
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#### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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